TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (U-MOSVI-H)

TPC8036-H

High Efficiency DC-DC Converter Applications Notebook PC Applications Portable Equipment Applications

- Small footprint due to a small and thin package
- High-speed switching

WW

- Small gate charge: Q_{SW} = 13 nC (typ.)
- Low drain-source ON-resistance: $R_{DS}(ON) = 3.1 \text{ m}\Omega \text{ (typ.)}$
- High forward transfer admittance: $|Y_{fs}| = 64 \text{ S} (typ.)$
- Low leakage current: $I_{DSS} = 10 \ \mu A \ (max) \ (V_{DS} = 30 \ V)$
- Enhancement mode: V_{th} = 1.3 to 2.3 V (V_{DS} = 10 V, I_D = 0.5 mA)

Absolute Maximum Ratings (Ta = 25°C)

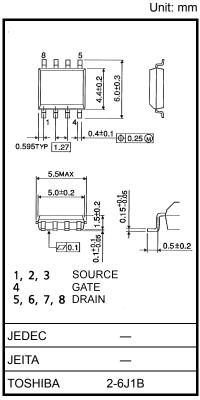
	Characte	eristic	Symbol	Rating	Unit	
	Drain-source voltage		V _{DSS}	30	V	
	Drain-gate voltage (F	R _{GS} = 20 kΩ)	V _{DGR}	30	V	
	Gate-source voltage		V _{GSS}	±20	V	
	Drain current	DC (Note 1)	ID	18	А	
		Pulsed (Note 1)	I _{DP}	72	A	
	Drain power dissipati	on (t = 10 s) (Note 2a)	PD	1.9	W	
w.Data\$	Drain power dissipati	on (t = 10 s) (Note 2b)	PD	1.0	W	
	Single pulse avalanc	he energy (Note 3)	E _{AS}	211	mJ	
	Avalanche current		I _{AR}	18	А	
	Repetitive avalanche (energy Note 2a) (Note 4)	E _{AR}	0.13	mJ	
	Channel temperature	9	T _{ch}	150	°C	
	Storage temperature	range	T _{stg}	–55 to 150	°C	

Note: For Notes 1 to 4, refer to the next page.

Using continuously under heavy loads (e.g. the application of high

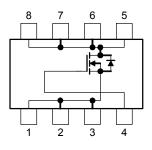
temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

This transistor is an electrostatic-sensitive device. Handle with care.



Weight: 0.085 g (typ.)

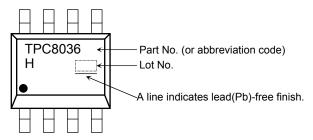
Circuit Configuration



Thermal Characteristics

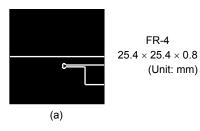
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to ambient $(t = 10 \text{ s})$ (Note 2a)	R _{th (ch-a)}	65.8	°C/W
Thermal resistance, channel to ambient $(t = 10 \text{ s})$ (Note 2b)	R _{th (ch-a)}	125	°C/W

Marking (Note 5)

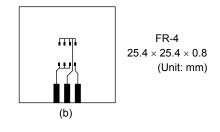


Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: (a) Device mounted on a glass-epoxy board (a)



(b) Device mounted on a glass-epoxy board (b)



Note 3: $V_{DD} = 24$ V, $T_{ch} = 25^{\circ}C$ (initial), L = 500 μ H, R_G = 25 Ω , I_{AR} = 18 A

www.DataSNotel4:coRepetitive rating: pulse width limited by maximum channel temperature

Note 5: • on lower left of the marking indicates Pin 1.

* Weekly code: (Three digits)



Week of manufacture _(01 for the first week of the year: sequential number up to 52 or 53)

- Year of manufacture

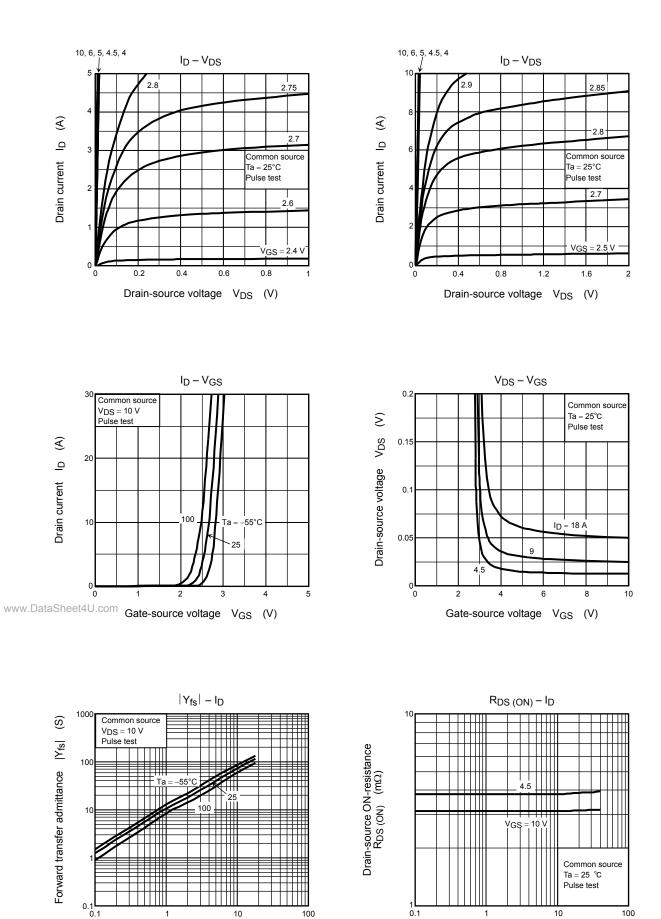
(The last digit of the year)

Electrical Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	$V_{GS}=\pm 20~V,~V_{DS}=0~V$		_	±100	nA
Drain cut-OFF cu	rrent	I _{DSS}	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_	_	10	μA
Drain-source breakdown voltage		V (BR) DSS	$I_{D} = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	30	_	—	- V
		V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	15	_	_	
Gate threshold vo	bltage	V _{th}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 0.5 \text{ mA}$	1.3	_	2.3	V
Drain-source ON-resistance Forward transfer admittance		Pro (ou)	$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 9 \text{ A}$	_	3.7	5.1	mΩ
		R _{DS (ON)}	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 9 \text{ A}$	_	3.1	4.5	
		Y _{fs}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 9 \text{ A}$	32	64	—	S
Input capacitance		C _{iss}		_	3500	4600	pF
Reverse transfer capacitance		C _{rss}	V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz	_	230	370	
Output capacitance		C _{oss}		_	690	_	
Gate resistance	te resistance		V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz	_	1.0	1.5	Ω
	Rise time	tr	$V_{GS} \stackrel{10}{}_{0}V \prod I_{D} = 9 A$		4.5	_	ns
Switching time	Turn-on time	t _{on}			14	_	
Switching time	Fall time	t _f		_	7.4	_	
	Turn-off time	t _{off}	$V_{DD} \approx 15 \text{ V}$ Duty \leq 1%, $t_W = 10 \ \mu s$	_	46	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD}\approx 24~V,~V_{GS}=10~V,~I_{D}=18~A$	_	49	_	
			$V_{DD}\approx 24~V,~V_{GS}=5~V,~I_{D}=18~A$	_	26	_	
Gate-source charge 1		Q _{gs1}	$V_{DD} \approx 24$ V, $V_{GS} = 10$ V, $I_D = 18$ A	_	10		nC
Gate-drain ("miller") charge		Q _{gd}		_	7.7		
Gate switch charge		Q _{SW}]	_	13	—	

www.DaSource-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Drain reverse current	Pulse	(Note 1)	I _{DRP}	—	_	_	72	А
Forward voltage (diode)		V _{DSF}	$I_{DR} = 18 \text{ A}, V_{GS} = 0 \text{ V}$			-1.2	V	



100

10

1

Drain current ID (A)

10

1

Drain current ID (A)

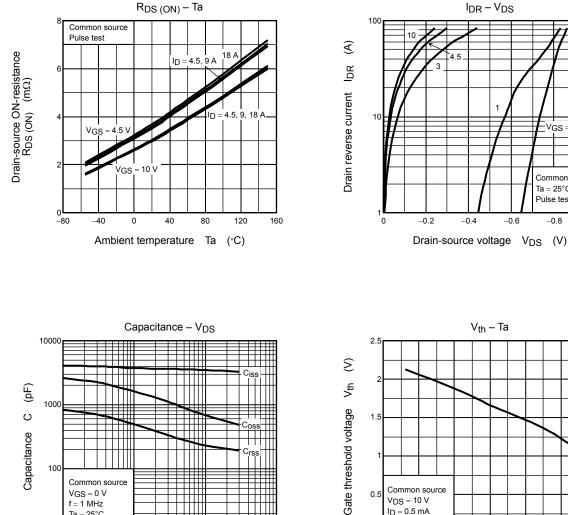
100

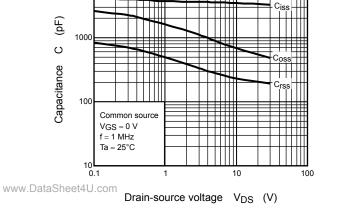
VGS = 0 V

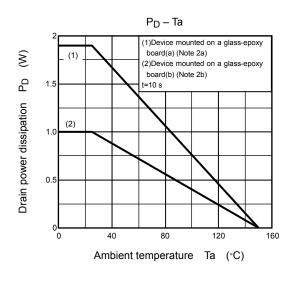
Common source Ta = 25°C Pulse test

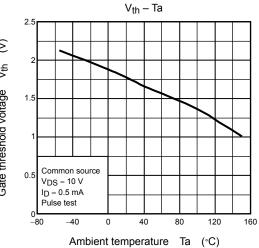
-0.8

-1.0





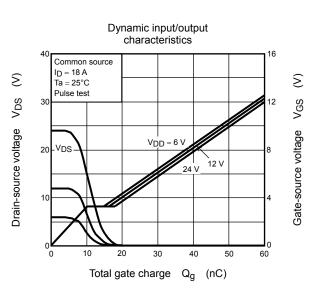


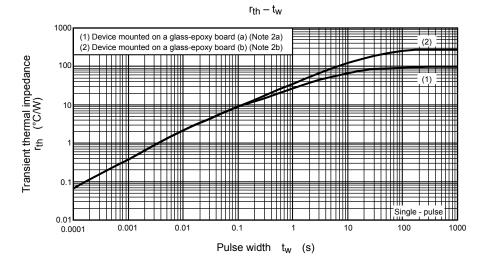


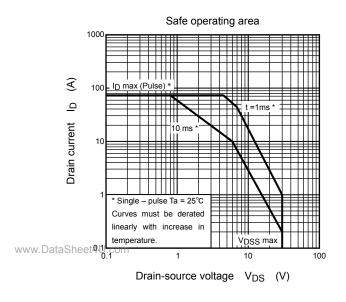
-0.4

-0.6

IDR - VDS







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20070701-EN GENERAL

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